

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination MAEDA ET AL.	
		Examiner Jason M Han	Art Unit 2875	Page 1 of 1

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-5,712,694	01-1998	Taira et al.	349/9
B	US-			
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J	US-			
K	US-			
L	US-			
M	US-			

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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